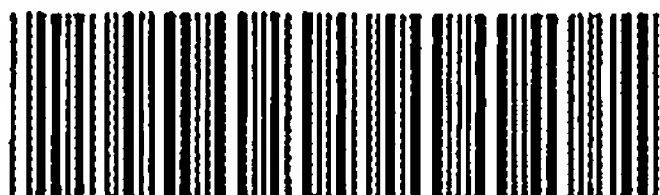


# Search Notes



Application/Control No.

10/651,663

Examiner

Yuwen Pan

Applicant(s)/Patent under  
Reexamination

XIE, FEI

Art Unit

2682

## SEARCHED

Class	Subclass	Date	Examiner
405	412.1 412.2 550.1	10/12/05	yw
	556.2		
707	205		
704	210	4/18/06	yw
	211		
	207		
	208		
	209		
	217		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Lewis West	10/12/05	yw
han, Qi	4/18/06	yw